

BS EN 62417:2010



BSI Standards Publication

Semiconductor devices — Mobile ion tests for metal-oxide semiconductor field effect transistors (MOSFETs)

National foreword

This British Standard is the UK implementation of EN 62417:2010. It is identical to IEC 62417:2010.

The UK participation in its preparation was entrusted to Technical Committee EPL/47, Semiconductors.

A list of organizations represented on this committee can be obtained on request to its secretary.

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